NTD-261

SER 20 TOM TRADELLE

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

Y. TAKEZAWA et al.

Serial No. 10/082,282

Group Art Unit 2878

Filed: February 26, 2002

Examiner: D. Monbleau

For:

METHOD AND APPARATUS OF DIAGNOSING DETERIORATION

OF AN ARTICLE

## REQUEST FOR INITIALED FORMS PTO-1449

Box: Issue Fee

Commissioner for Patents Alexandria, Virginia 22314

September 20, 2004

Sir:

Applicants respectfully request the Examiner to initial and return the attached copies of the Forms PTO 1449 (2 pages) filed with an Information Disclosure Statement on February 26, 2002, as an indication that the ten cited documents have been considered. A copy of the date-stamped mailroom receipt as evidence of receipt of the U.S. Patent and Trademark Office is being submitted herewith.

Respectfully submitted,

Daniel J. Stanger Registration No. 32,846

Attorney for Applicants

MATTINGLY, STANGER & MALUR, P.C. 1800 Diagonal Rd., Suite 370 Alexandria, VA 22314 (703) 684-1120

Date: September 20, 2004





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